

Test Report

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GREAT WALL SEMICONDUCTOR (GWS)
7855 SOUTH RIVER PARKWAY SUITE 122 TEMPE, AZ 85284, USA



The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description : 20V BI-DIRECTIONAL MOSFET IN TSOP JW-8 PACKAGE
Style/Item No. : GWS7301E, GWS7301-0, GWS7301E-24, GWS7301A,
GWS7302E, GWS7304E, GWS8601
Sample Receiving Date : 2008/04/10
Testing Period : 2008/04/10 TO 2008/04/17

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Test Result(s) : Please refer to next page(s).



Chenyu Kung / Operation Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory – Taipei

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Test Result(s)

PART NAME NO.1 : 20V BI-DIRECTIONAL MOSFET IN TSOP JW-8 PACKAGE

Test Item (s):	Unit	Method	MDL	Result
				No.1
Cadmium (Cd)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Cadmium by ICP-AES.	2	n.d.
Lead (Pb)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Lead by ICP-AES.	2	n.d.
Mercury (Hg)	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Mercury by ICP-AES.	2	n.d.
Hexavalent Chromium Cr(VI) by alkaline extraction	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of Hexavalent Chromium for non-metallic samples by UV/Vis Spectrometry.	2	n.d.
Halogen	---	With reference to BS EN 14582:2007. Analysis was performed by IC method for F , Cl , Br, I content.	---	---
Halogen-Fluorine (F) (CAS No.: 007782-41-4)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Fluorine content.	50	n.d.
Halogen-Chlorine (Cl) (CAS No.: 007782-50-5)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Chlorine content.	50	n.d.
Halogen-Bromine (Br) (CAS No.: 007726-95-6)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Bromine content.	50	2490
Halogen-Iodine (I) (CAS No.: 007553-56-2)	mg/kg	With reference to BS EN 14582:2007. Analysis was performed by IC method for Iodine content.	50	n.d.

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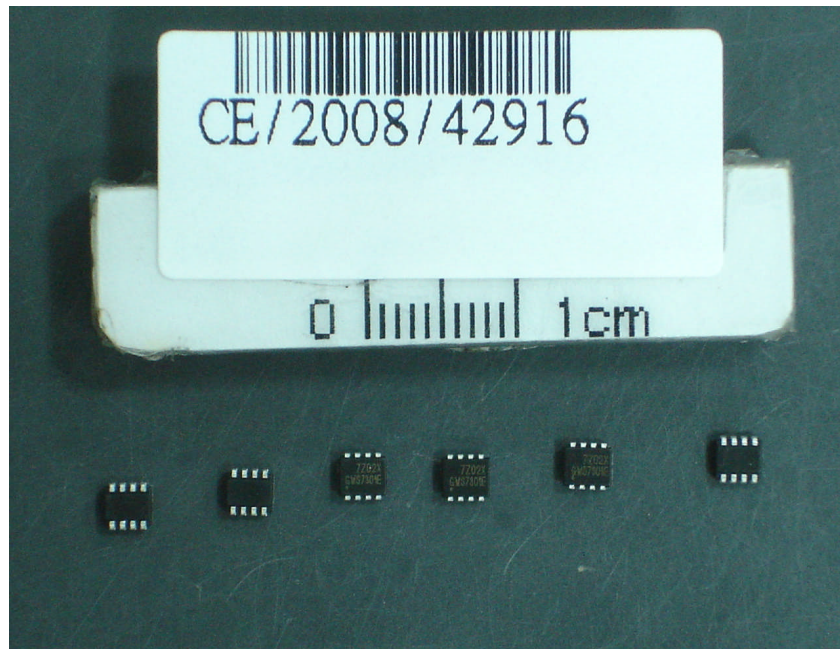
Test Item (s):	Unit	Method	MDL	Result
				No.1
Sum of PBBs	mg/kg	With reference to IEC 62321/2nd CDV (111/95/CDV). Determination of PBB and PBDE by GC/MS.	-	n.d.
Monobromobiphenyl			5	n.d.
Dibromobiphenyl			5	n.d.
Tribromobiphenyl			5	n.d.
Tetrabromobiphenyl			5	n.d.
Pentabromobiphenyl			5	n.d.
Hexabromobiphenyl			5	n.d.
Heptabromobiphenyl			5	n.d.
Octabromobiphenyl			5	n.d.
Nonabromobiphenyl			5	n.d.
Decabromobiphenyl			5	n.d.
Sum of PBDEs (Mono to Nona) (Note 4)			-	n.d.
Monobromodiphenyl ether			5	n.d.
Dibromodiphenyl ether			5	n.d.
Tribromodiphenyl ether			5	n.d.
Tetrabromodiphenyl ether			5	n.d.
Pentabromodiphenyl ether			5	n.d.
Hexabromodiphenyl ether			5	n.d.
Heptabromodiphenyl ether			5	n.d.
Octabromodiphenyl ether			5	n.d.
Nonabromodiphenyl ether			5	n.d.
Decabromodiphenyl ether			5	n.d.
Sum of PBDEs (Mono to Deca)			-	n.d.

- Note :
1. mg/kg = ppm
 2. n.d. = Not Detected
 3. MDL = Method Detection Limit
 4. According to 2005/717/EC DecaBDE is exempt.
 5. "---" = Not Conducted
 6. "- " = Not Regulated

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** End of Report **